	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
29	BRS	23	(((volume\$5 or voxel) same (slic\$4 or (cross adj section\$4))) same imag\$4) and ((slic\$4 or (cross adj section\$4)) near7 (centroid))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	S-PGPUB; 2004/09/17); IBM_TDB 17:25		
30	BRS	2102	382/141,144-150,284,294.ccls.	USPAT	2004/09/20 18:42		
31	BRS	19900	<pre>(die or wafer or semiconductor or (circuit nearl board)) near5 (inspect\$4 or imag\$4)</pre>	USPAT	2004/09/20 18:45		
32	BRS	21128	<pre>(die or wafer or semiconductor or (circuit near1 board)) near5 (inspect\$4 or imag\$4)</pre>	USPAT	2004/09/20 · 18:45		
33	BRS	7521	(die or wafer or semiconductor or (circuit nearl board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6)))	ISPAT	2004/09/20 19:06		
34	BRS	1619	((die or wafer or semiconductor or (circuit nearl board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6)))) same imag\$4	USPAT	2004/09/20 19:05		
м ъ	BRS	M	(((die or wafer or semiconductor or (circuit nearl board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6))) same imag\$4) and 382/284.ccls.	USPAT	2004/09/20 18:50		
36	BRS	2	382/141,144-150.ccls. and 382/284.ccls.	USPAT	2004/09/20 18:51		

e the manageria	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
37	BRS	28135	(die or wafer or semiconductor or (circuit nearl board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6)))	USPAT; US-PGPUB; 2004 EPO; JPO; DERWENT; IBM_TDB 20:5	2004/09/20 20:59		
38	BRS	4773	((die or wafer or semiconductor or (circuit nearl board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6)))) same imag\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/20 19:06		
39	BRS	28135	or wafer or semiconductor ircuit near1 board)) (inspect\$4 or ((defect\$3 ult\$3) near4 (detect\$4 or ni\$8 or analy\$9 or nin\$6)))	JSPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/20 19:06		
40	BRS	4773	((die or wafer or semiconductor or (circuit nearl board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6)))) same imag\$4	USPAT; US-PGPUB; 2004/09/20 EPO; JPO; DERWENT; IBM_TDB 19:23	2004/09/20 19:23		
41	BRS	564	(((die or wafer or semiconductor or (circuit nearl board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6))) same imag\$4) and (image near3 (composite or entire or whole))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	US-PGPUB; 2004/09/20 0; 1; IBM_TDB 19:07		

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
42	BRS	б б	(((die or wafer or semiconductor or (circuit near1 board)) near5 (inspect\$4 or (defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6))) same imag\$4) and (image near3 (composite))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/20 19:07		
4 8	BRS	146	fer or r or (circuit) near5 (inspect\$4 3 or fault\$3) t\$4 or recogni\$8 r determin\$6))) same (image near3 r entire or	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/20 19:07		
44	BRS	1 6	(((die or wafer or semiconductor or (circuit near1 board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6))) same imag\$4) same (image near3 (composite))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/20 19:08		
45	IS&R	4	(("6753972") or ("5301248") or ("5973777") or ("6072899")).PN.	USPAT	2004/09/20 19:14		
46	BRS	7	(((die or wafer or semiconductor or (circuit near1 board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6))) same imag\$4) and 382/284.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/20 19:32		

	Туре	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
47 BRS		16	(((die or wafer or semiconductor or (circuit nearl board)) near5 (inspect\$4 or ((defect\$3 or fault\$3) near4 (detect\$4 or recogni\$8 or analy\$9 or determin\$6)))) same imag\$4) and 382/284,294.ccls.	USPAT; US-PGPUB; 2004/09/20 EPO; JPO; DERWENT; IBM_TDB 19:32	2004/09/20	·	